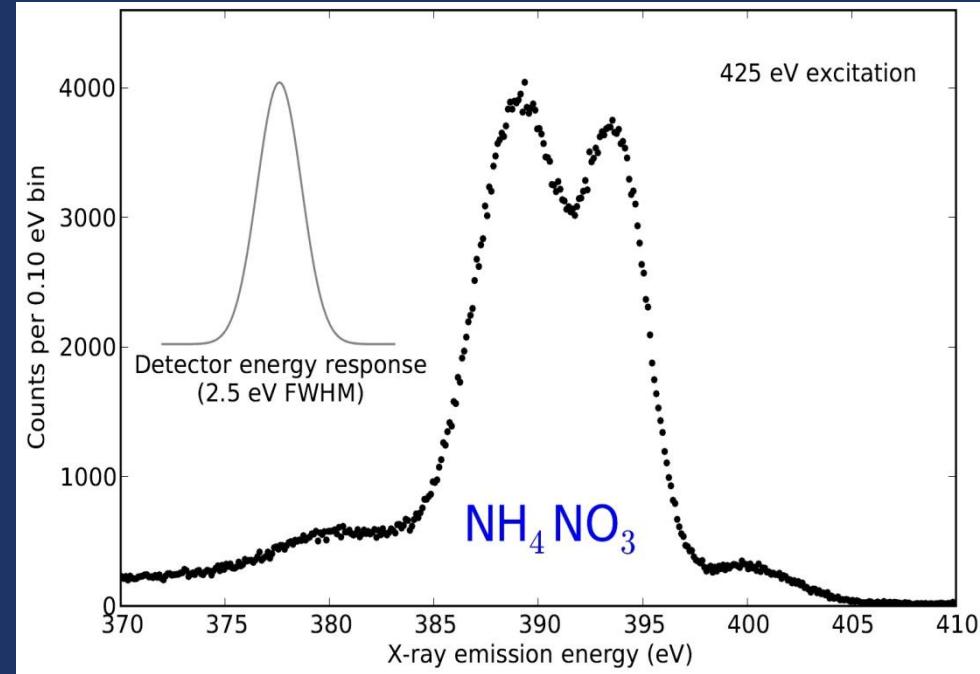
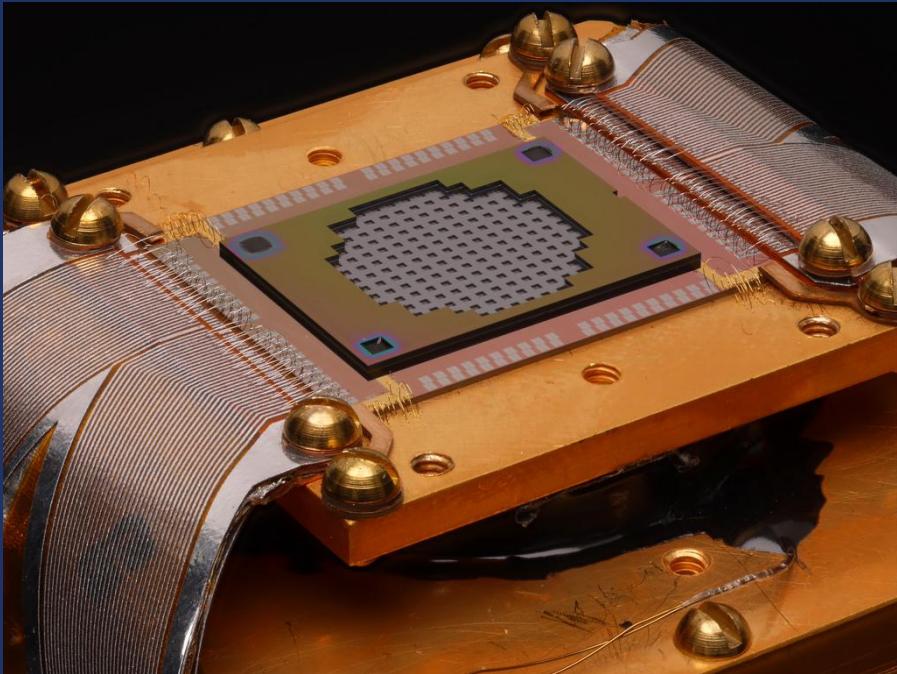


First synchrotron observations by the NIST microcalorimeter-spectrometer

Randy Doriese, NIST (Boulder, Colorado)



- 1) synchrotrons and X-ray spectroscopy
- 2) NIST TES spectrometer at NSLS beamline U7A
- 3) initial synchrotron spectroscopy results



collaborators

<u>NIST</u>	<u>(Boulder, CO)</u>	<u>NIST / NSLS</u>	<u>(Brookhaven, NY)</u>
Brad Alpert	Luis Miaja-Avila	Daniel Fischer	Bruce Ravel
Jim Beall	Carl Reintsema	Cherno Jaye	Joe Woicik
Doug Bennett	Frank Schima		
Colin Fitzgerald	Dan Schmidt		
Joe Fowler	Dan Swetz	Villy Sundström	Wilfred Fullagar
Gene Hilton	Jens Uhlig		
Rob Horansky	Joel Ullom		
Kent Irwin	Leila Vale	Ilari Maasilta	Kimmo Kinnunen
Vince Kotsubo		Mikko Palosaari	



acknowledgments

for help with samples, thanks to:

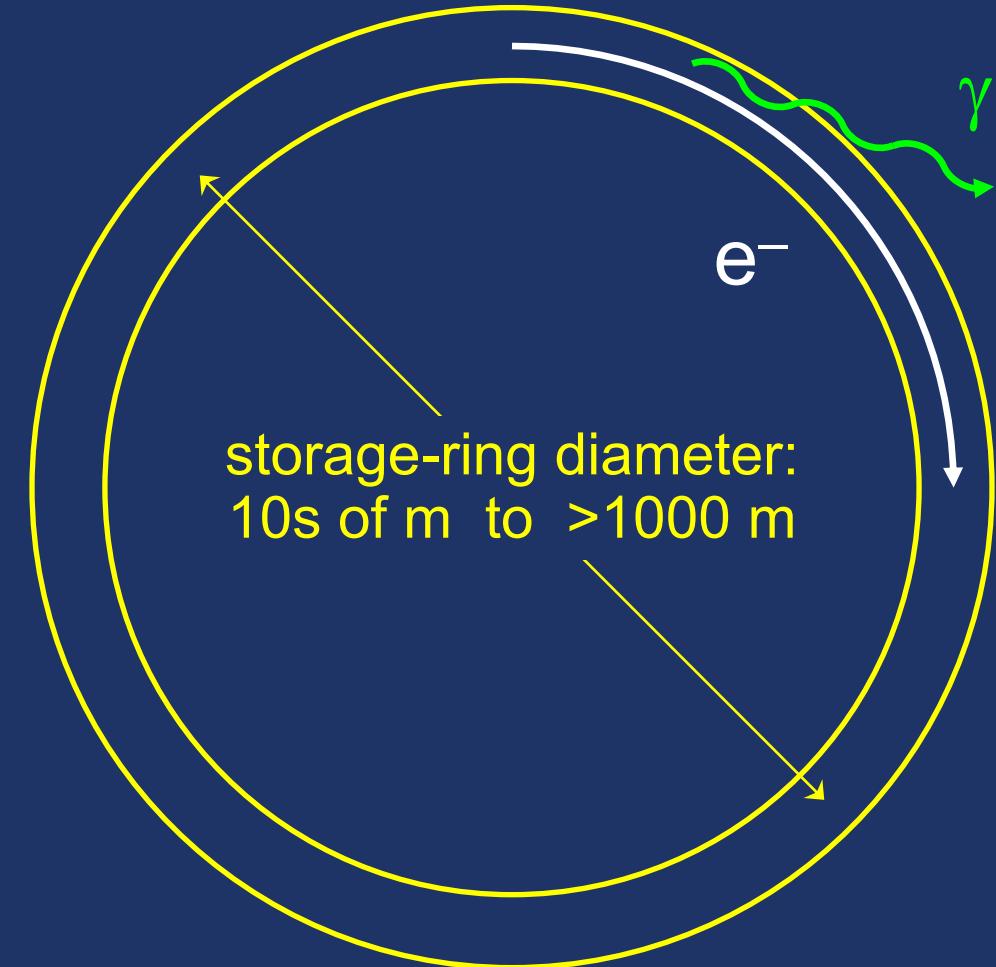
Josef Michl, Dan Dessau, Daniel Weingarten (University of Colorado)
Sean Shaheen (University of Denver)
Terry Jach, John Sieber, Clay Davis (NIST)

for useful discussions, thanks to:

Wanli Yang (Advanced Light Source)
Pieter Glatzel (ESRF)
Robin Cantor (Star Cryoelectronics)



synchrotrons: a brief review



Use accelerated electrons to make light.

important techniques:
X-ray absorption and emission spectroscopy



synchrotron spectroscopy

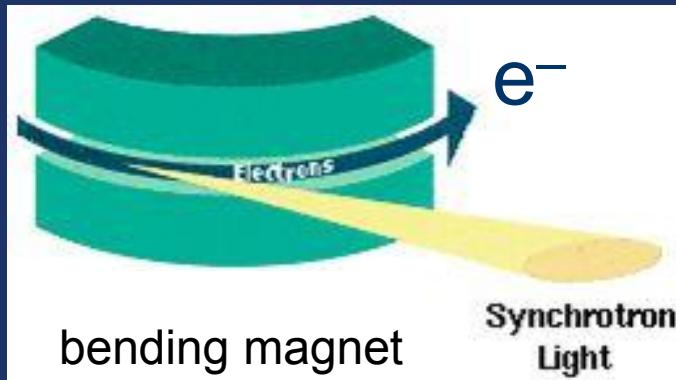
our spectrometer

results

NIST

anatomy of a synchrotron beamline

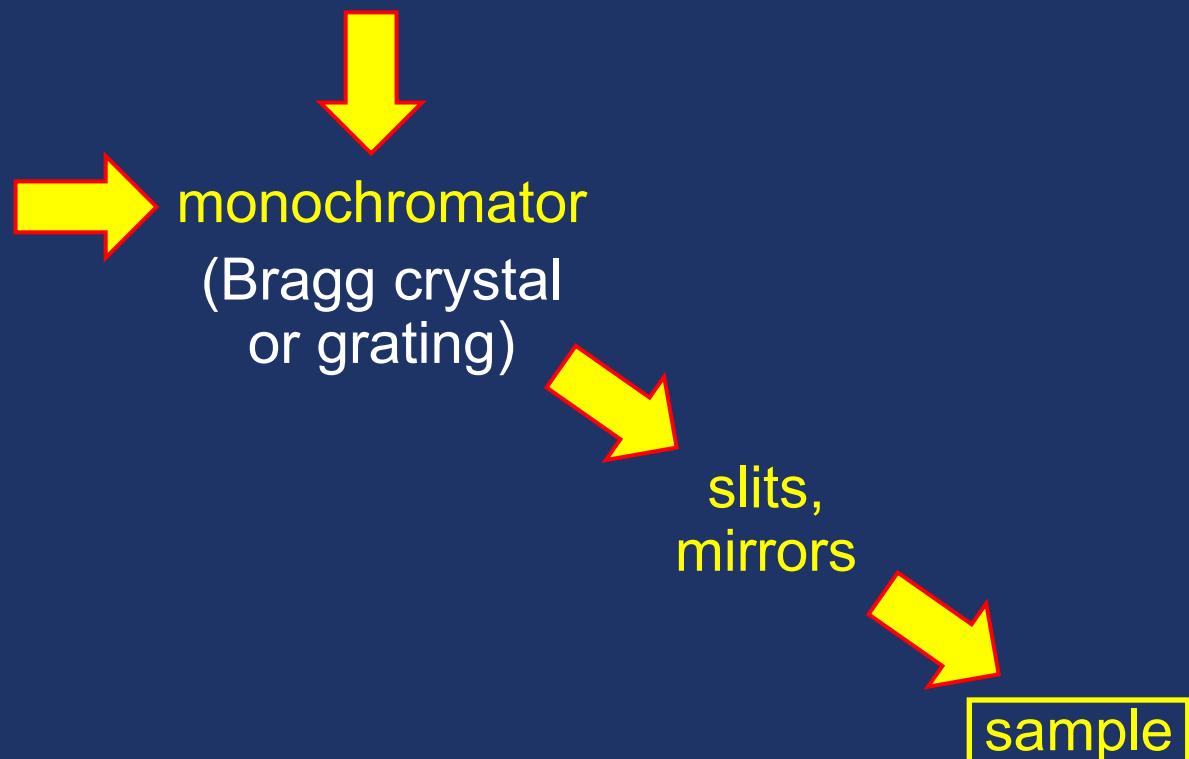
images
courtesy of
wikipedia



bending magnet

e^-

Synchrotron
Light



synchrotron spectroscopy

our spectrometer

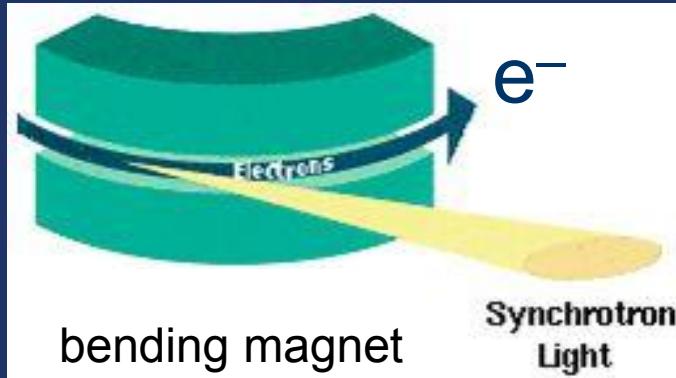
results

NIST

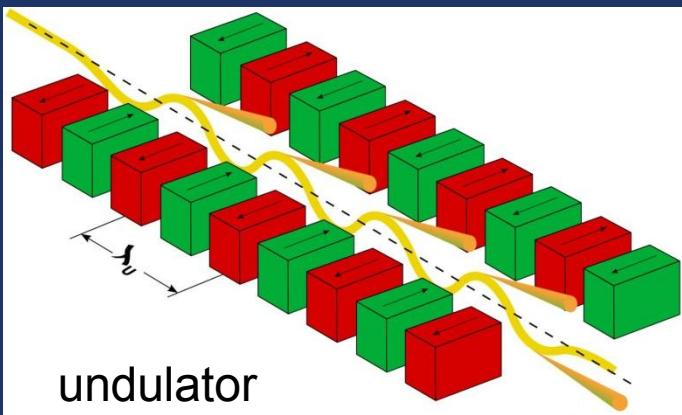
W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

anatomy of a synchrotron beamline

images
courtesy of
wikipedia



$\sim 10^9 - 10^{12} \text{ } \gamma / \text{s} / (0.1 \text{ eV})$



$\sim 10^{12} - 10^{14} \text{ } \gamma / \text{s} / (0.1 \text{ eV})$

resulting beam:

- large flux
- monochromatic
- can be highly focused
- polarized



synchrotron spectroscopy

our spectrometer

results

NIST

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

high-res X-ray emission spectroscopy (XES)

present high-res. X-ray emission spectrometers are wavelength-dispersive.

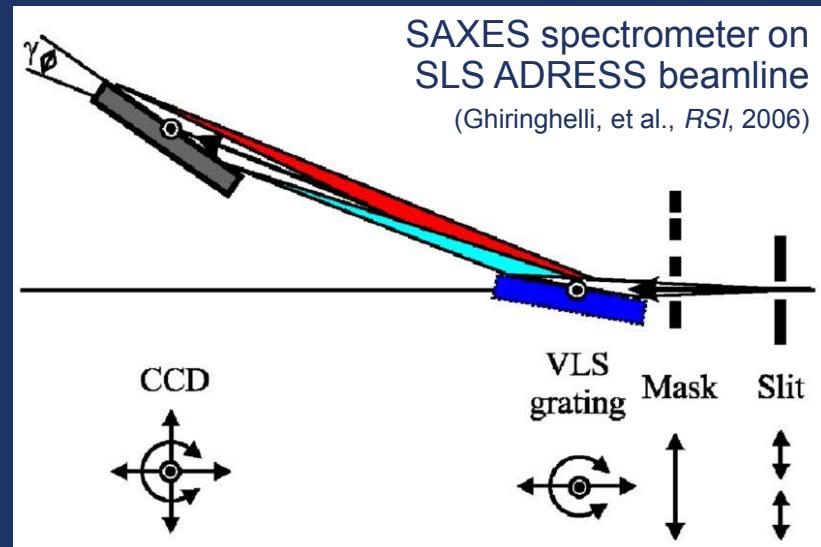
the good: energy resolution.

- typical $E/\Delta E \sim 1,000 - 3,000$
- best $E/\Delta E$ can be $> 10,000$

the bad: collection efficiency

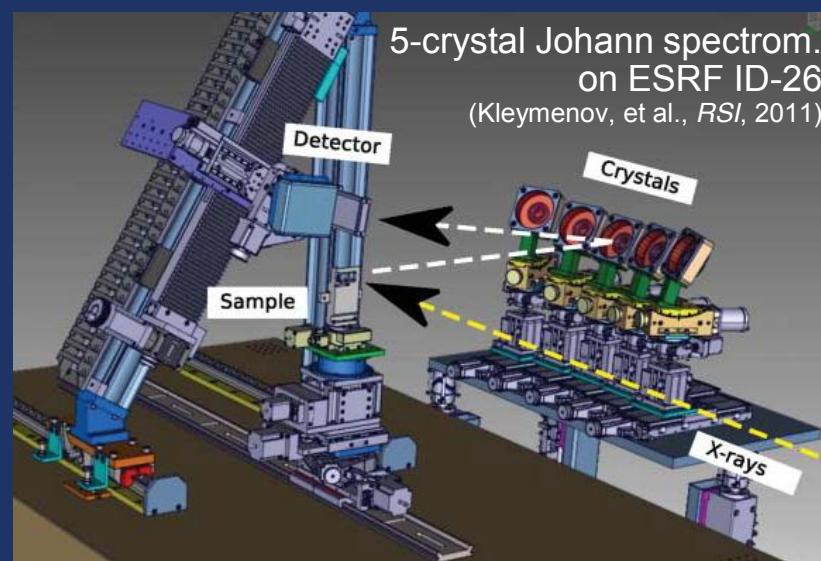
- poor solid-angle coverage
- poor QE
- some must scan E

< 1.5 keV:
gratings



SAXES spectrometer on SLS ADRESS beamline
(Ghiringhelli, et al., *RSI*, 2006)

> 2 keV:
bent crystals



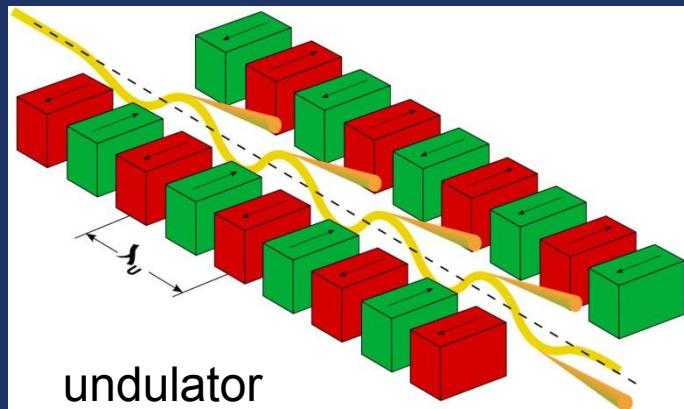
synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

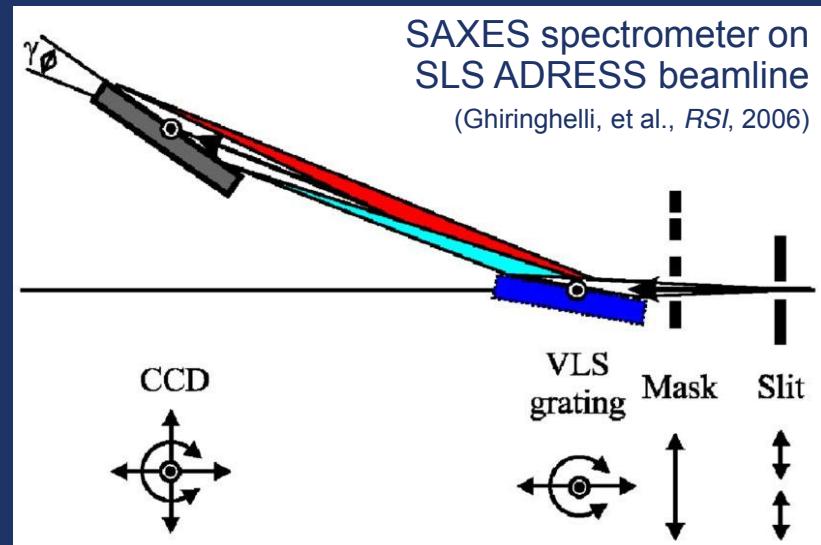
high-res X-ray emission spectroscopy (XES)

require:



$\sim 10^{12} - 10^{14}$ $\gamma / s / (0.1 \text{ eV})$

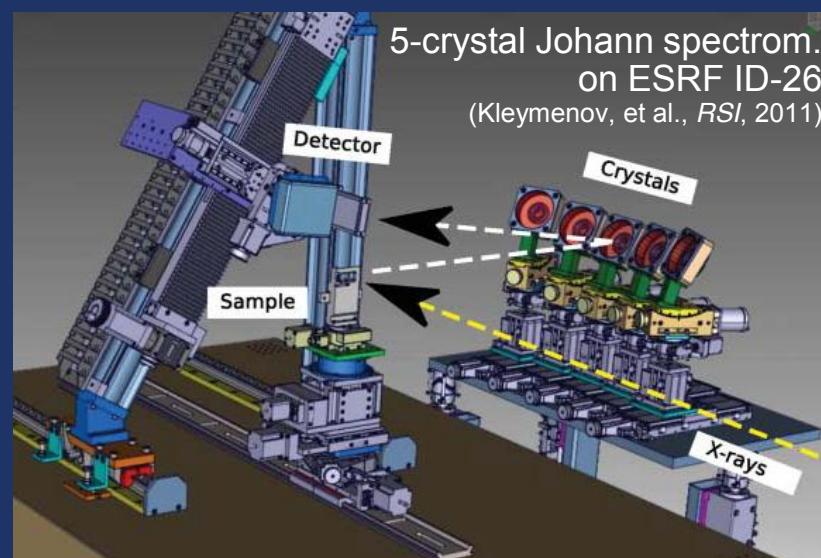
< 1.5 keV:
gratings



SAXES spectrometer on
SLS ADRESS beamline
(Ghiringhelli, et al., *RSI*, 2006)

- can easily damage sample
- some applications
(e.g. time-resolved)
still photon-starved

> 2 keV:
bent crystals



synchrotron spectroscopy

our spectrometer

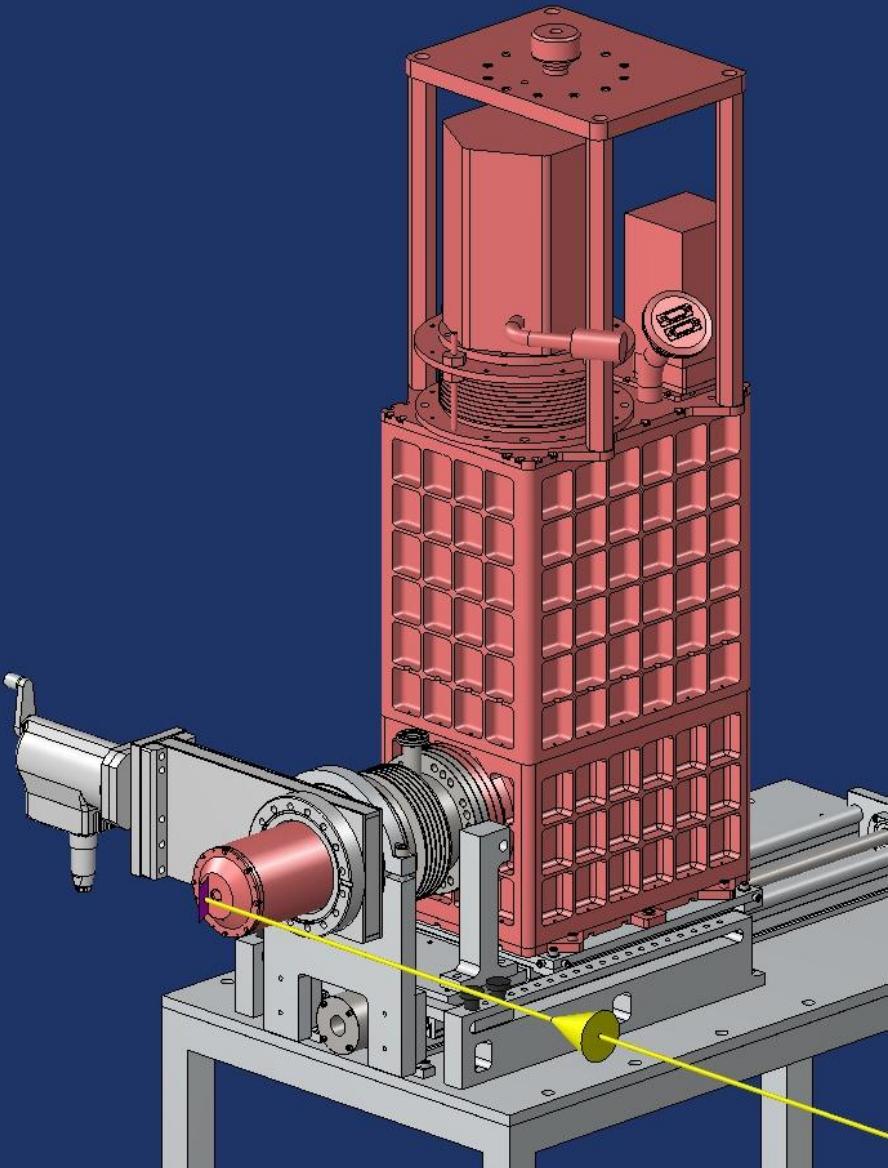
results

NIST

TES arrays for synchrotron-XES

How do TES arrays compare?

- ΔE : eV-scale
to see chemical shifts
- large solid-angle coverage
- high QE
- see entire spectral ROI at once
- count rate: generally want
*1 MHz or better for synchrotron
spectroscopy.*



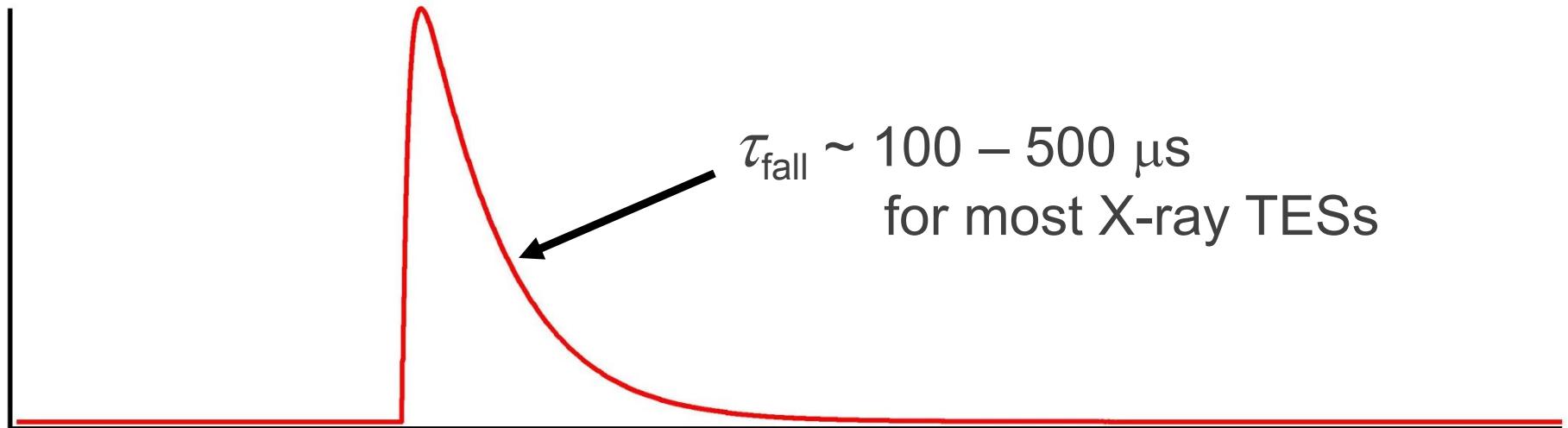
synchrotron spectroscopy

our spectrometer

results

NIST

TES count rate



“optimal filter” [Szymkowiak, *JLTP* (1993)]:

- requires one γ / record
- limited to 10s of Hz / TES for highest resolution with practical X-ray-TES time constants



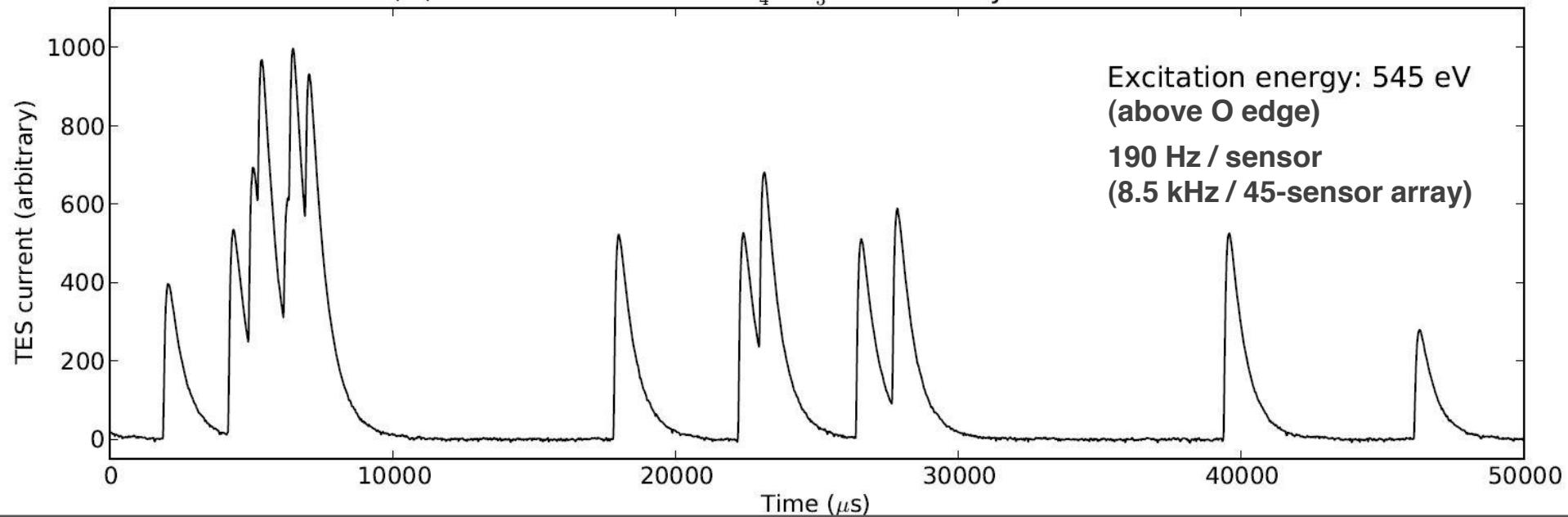
synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

TES count rate

C,N,O K α emission from NH₄NO₃ recorded by one TES detector



but what if data look like this?...

want *simultaneous* optimal filtering of $>>1 \gamma$ / data-record



synchrotron spectroscopy

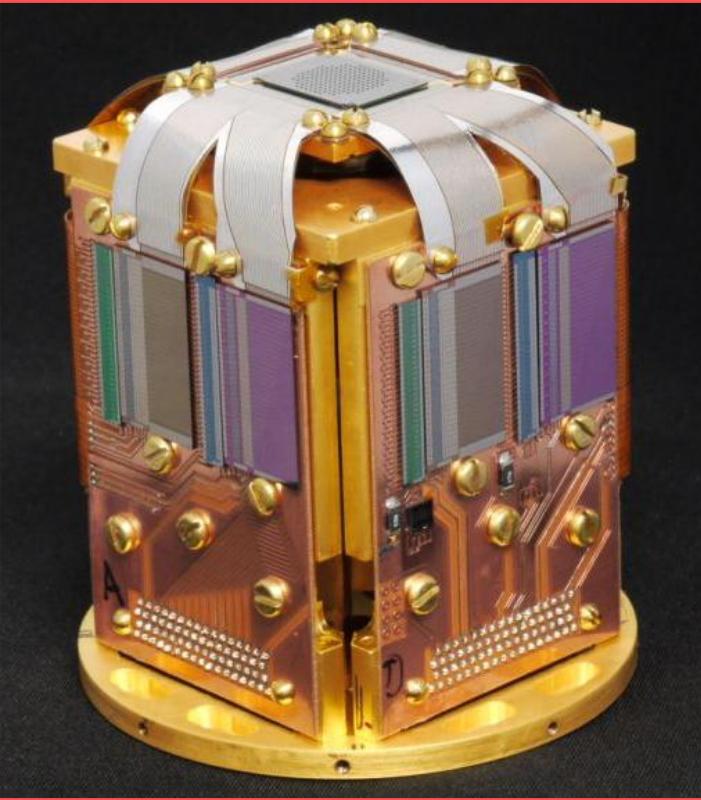
our spectrometer

results

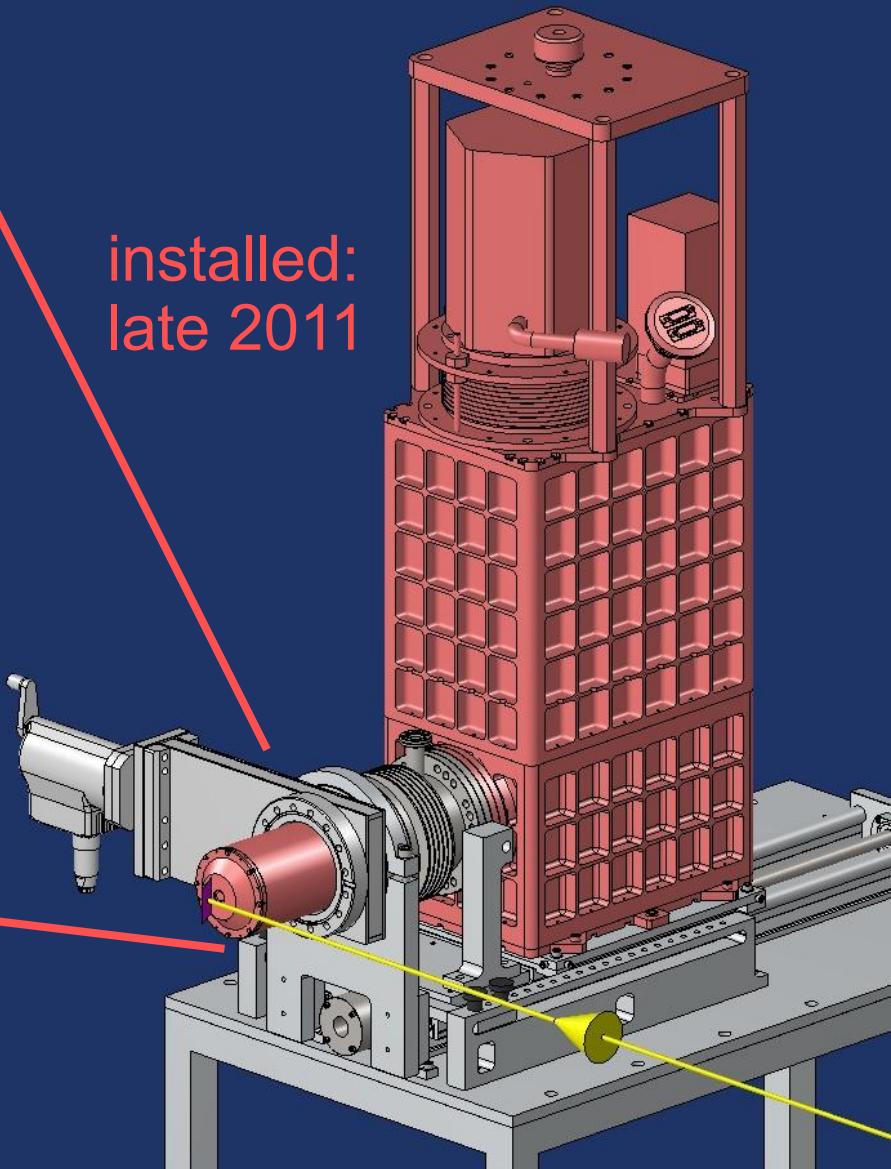
NIST

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

installed TES spectrometer



installed:
late 2011



NSLS U7A:
soft-X-ray (200–800 eV)
spectroscopy beamline.



synchrotron spectroscopy

our spectrometer

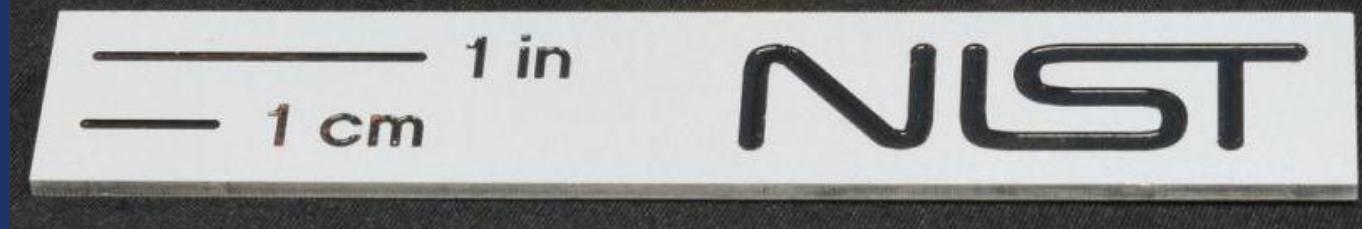
results

NIST

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

50 mK detector snout

- TES array on top
- TDM/CDM readout for up to 256 sensors (8col X 32row) around sides
- 50 mK bath: ADR
(see *ASC exhibitor HPD*)
- architecture could be grown to 1,024 TESs (32c X 32r) straightforwardly



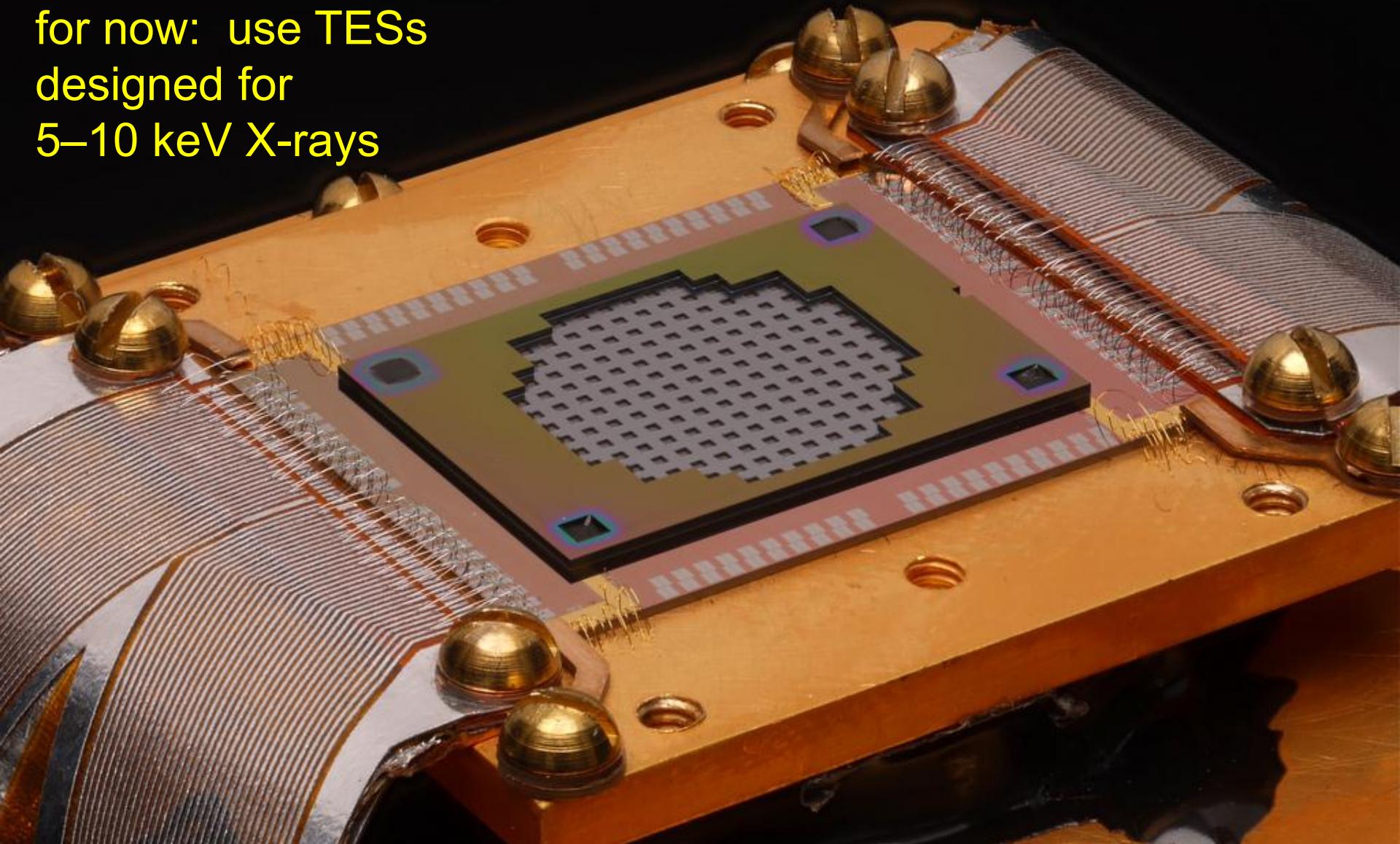
synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

detector plane

for now: use TESS
designed for
5–10 keV X-rays

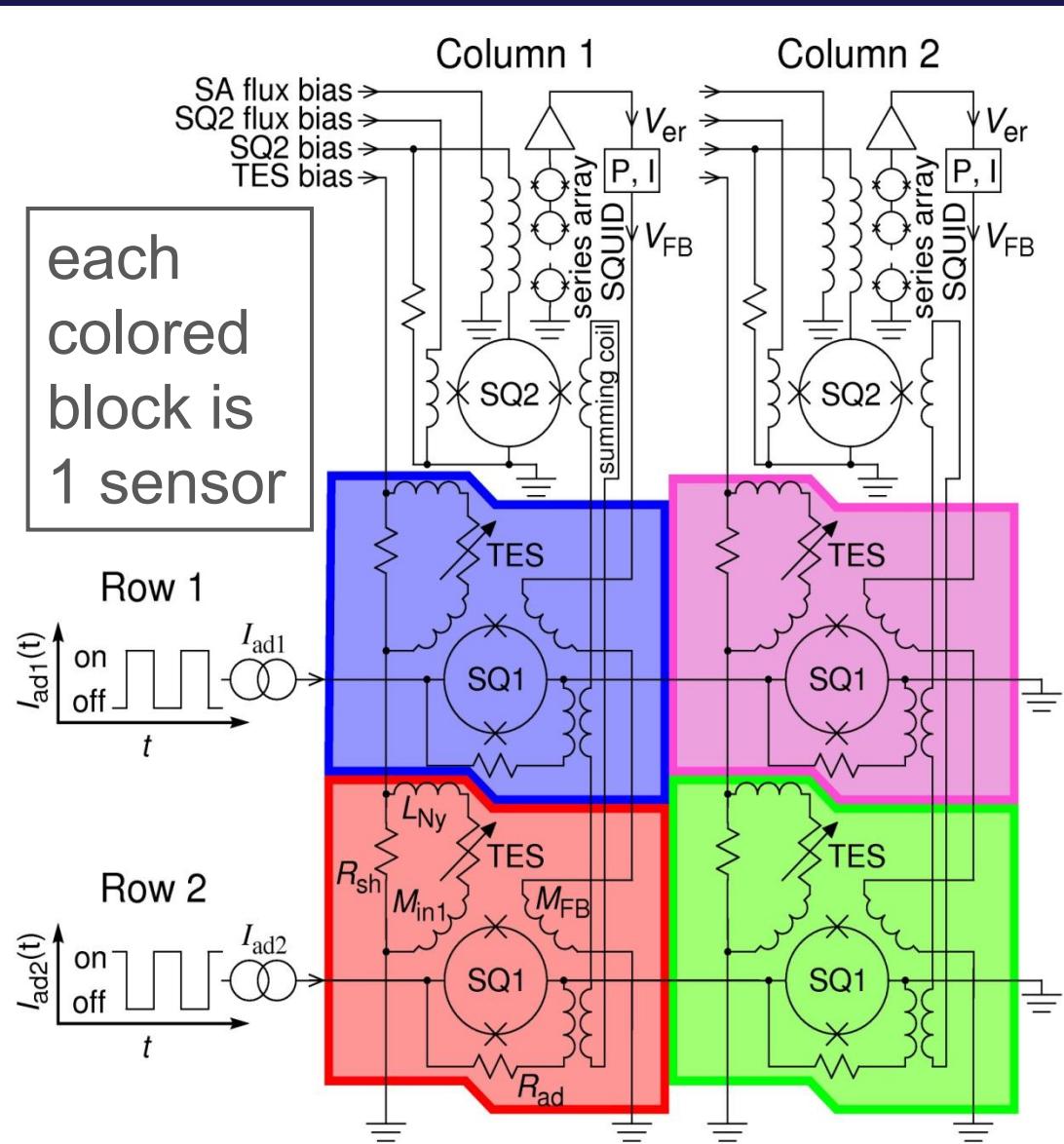


synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

TDM readout



- initial setup:
45 sensors wired into
3 col x 20 row TDM
- will soon wire up full
256 sensors



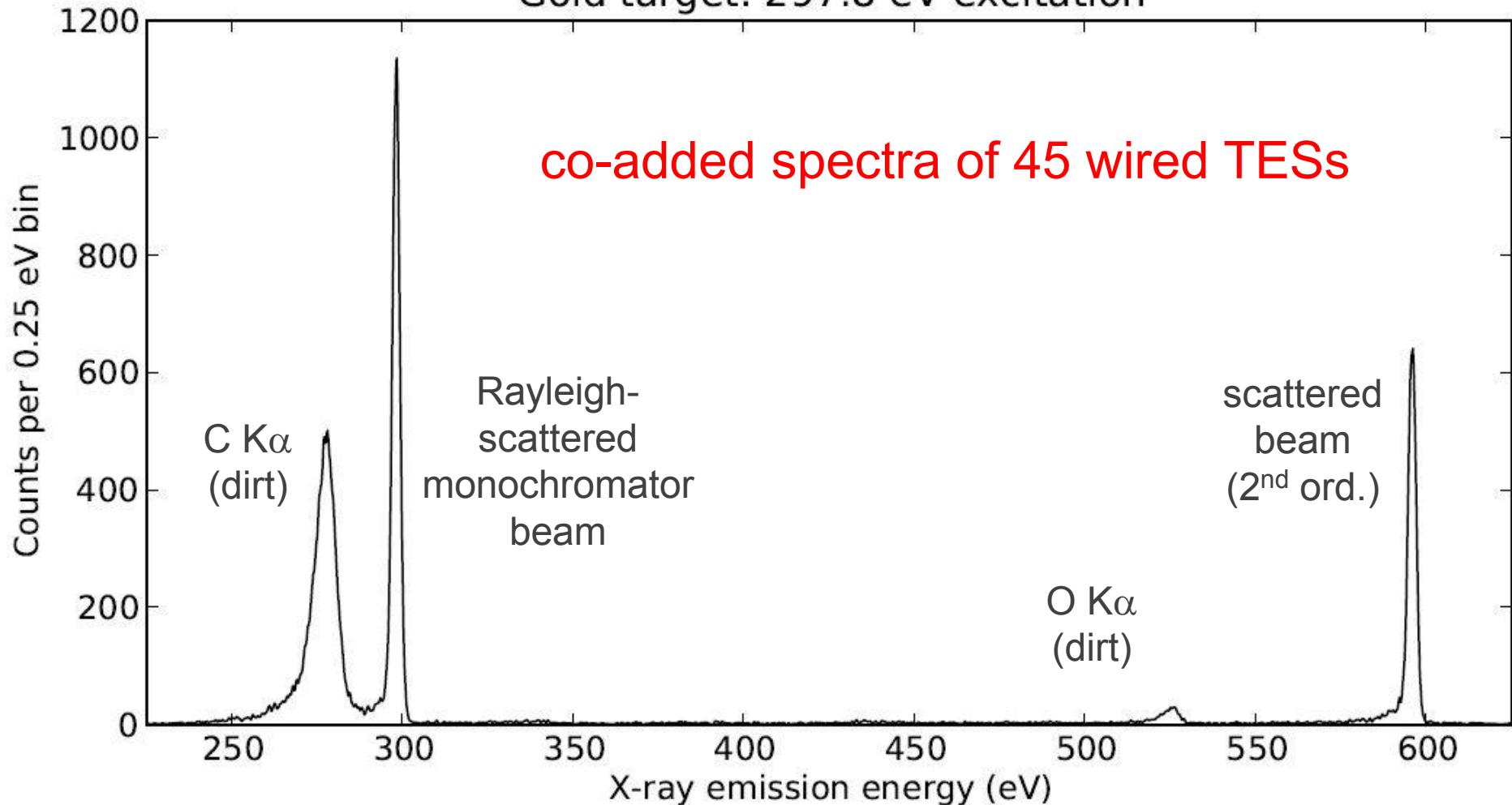
synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

achieved energy resolution

Gold target: 297.8 eV excitation

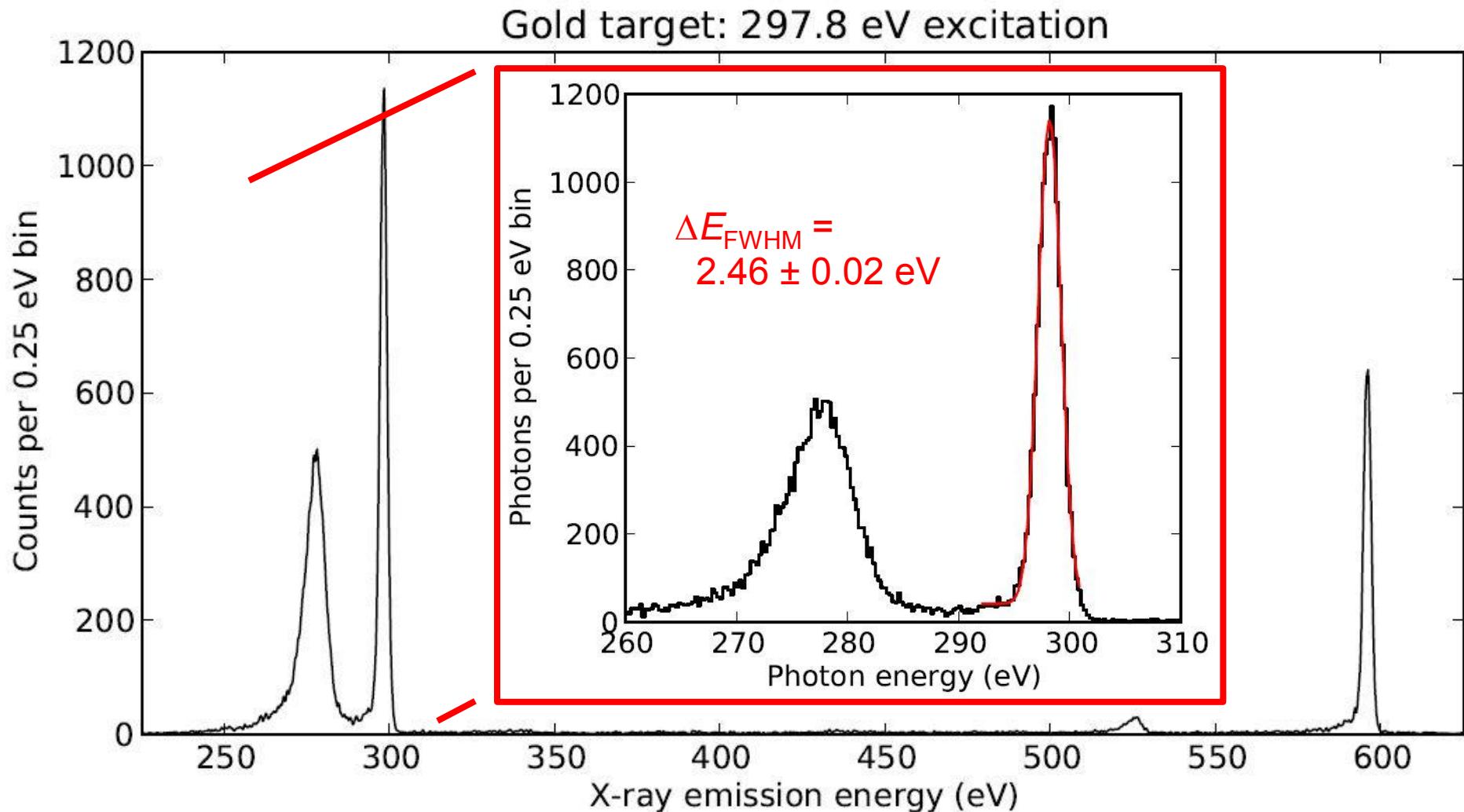


synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

achieved energy resolution

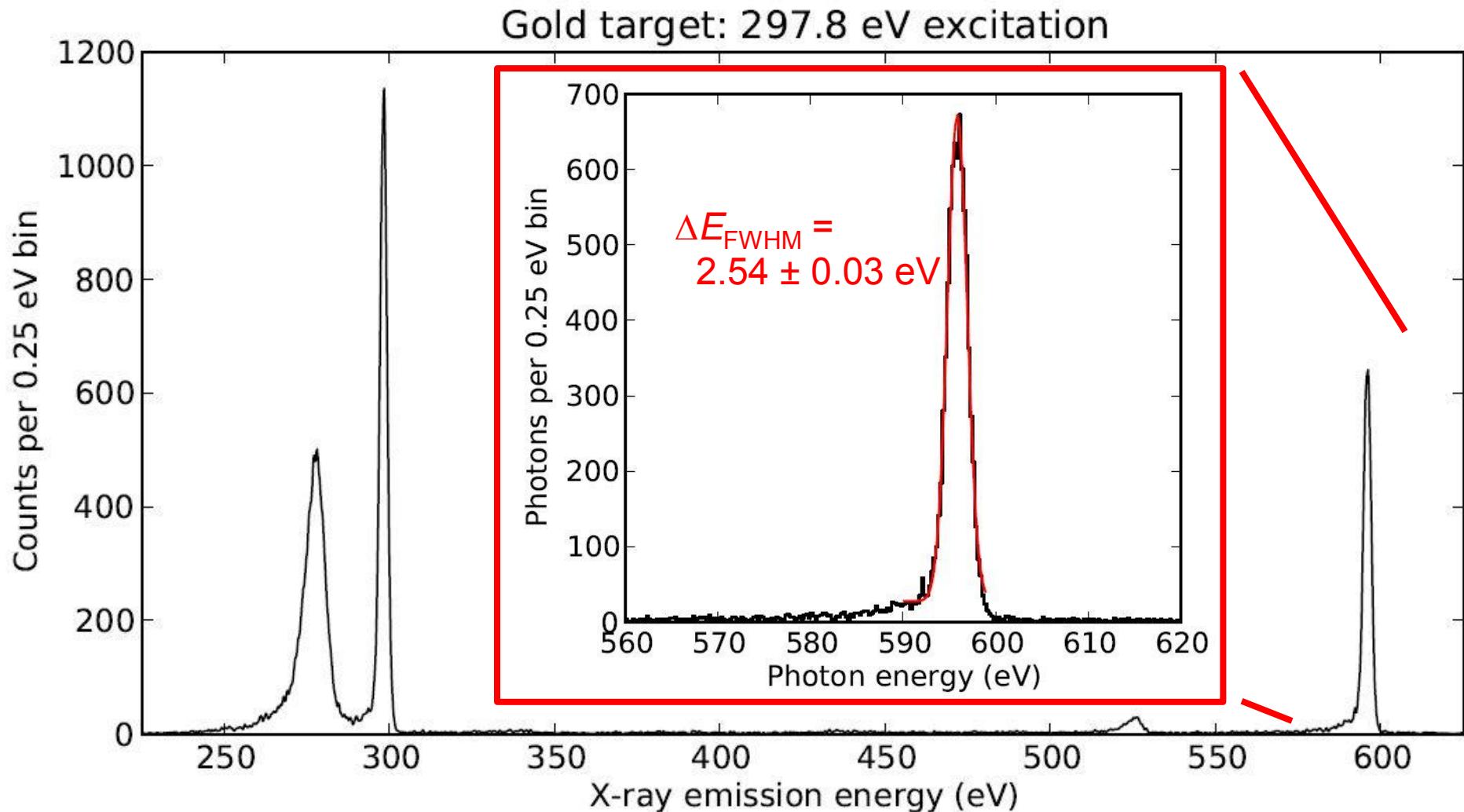


synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

achieved energy resolution



synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

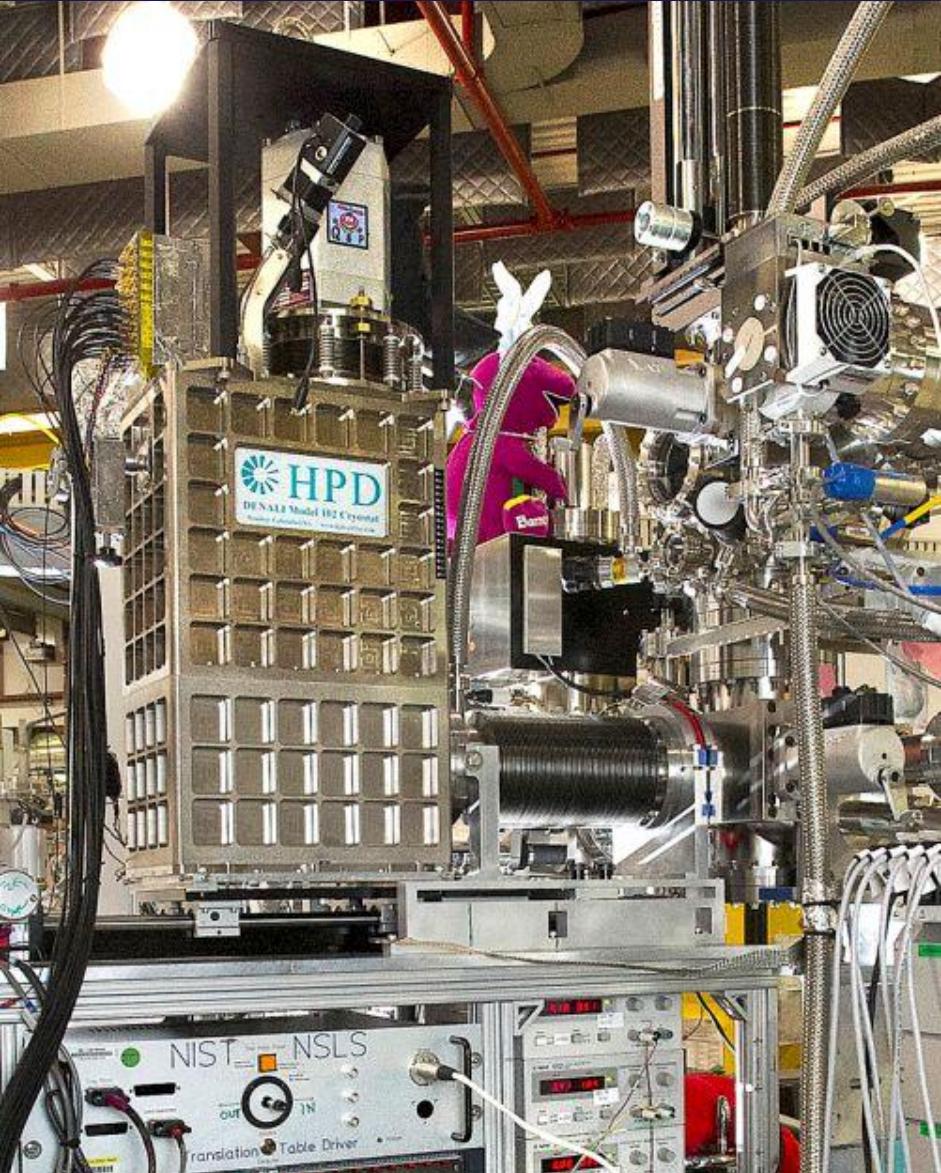
NIST

applications

applications:

- eV-scale X-ray emission spectroscopy
(chemistry of *occupied* valence states)
- partial-fluorescence-yield absorption spectroscopy
(chemistry of *unoccupied* valence states)

Let's see an example of each!



synchrotron spectroscopy

our spectrometer

results

NIST

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

chemical-shift XES

first example application:

X-ray emission spectroscopy (XES)
for chemical analysis

map occupied D.O.S.

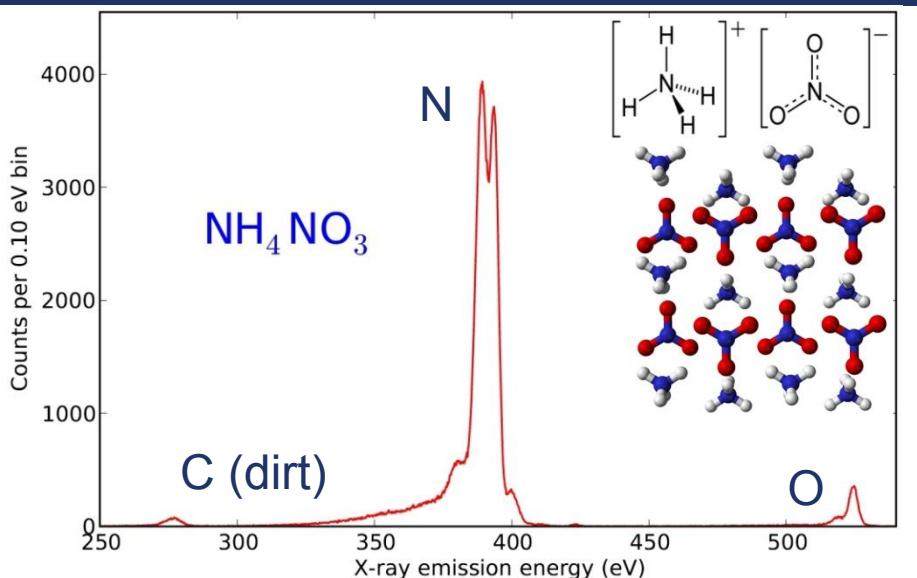
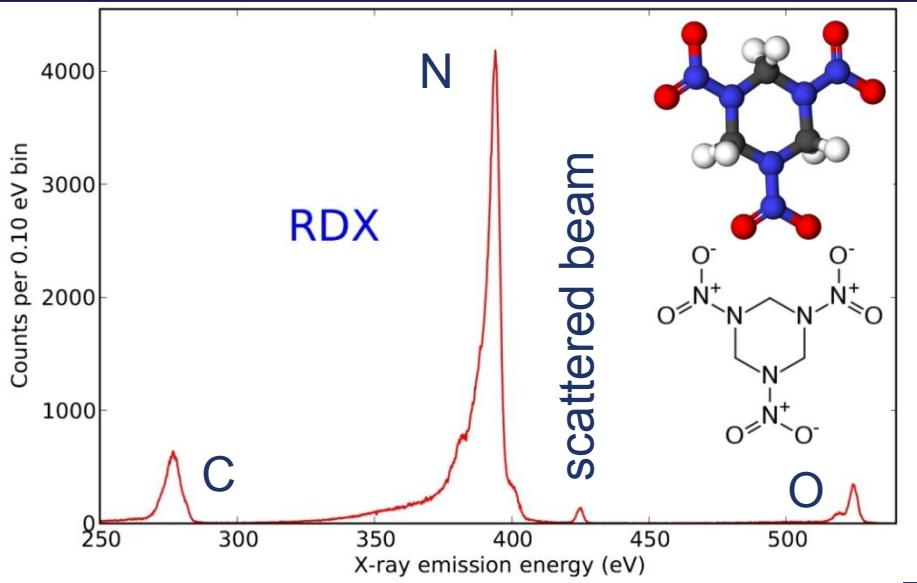


synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

chemical-shift XES



NIST is cataloging XES of “energetic nitrogen compounds” to aid SEM analysis of criminal forensic samples.

- RDX: major component of C4 plastic explosive
- ammonium nitrate (fertilizer; can be used to build fertilizer bombs)

excite @ 425 eV
(well above N edge).



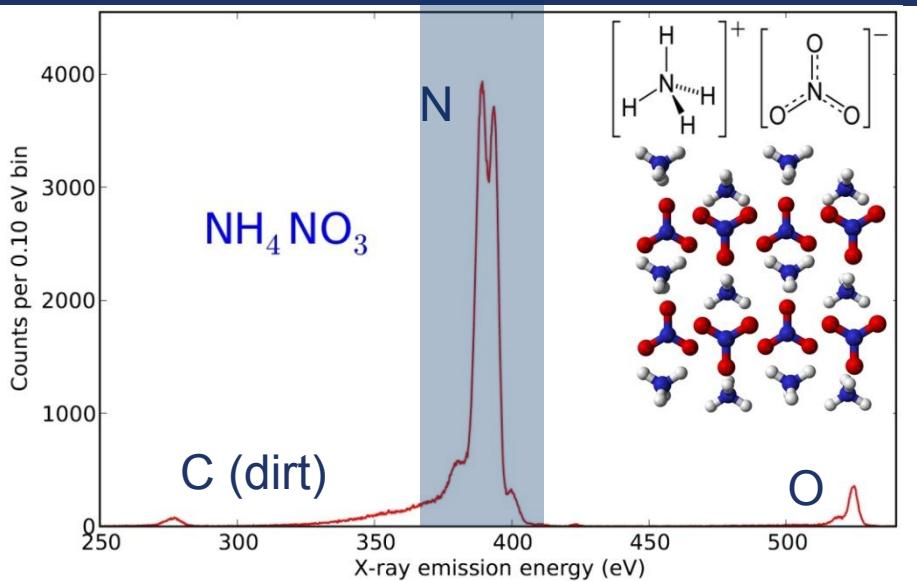
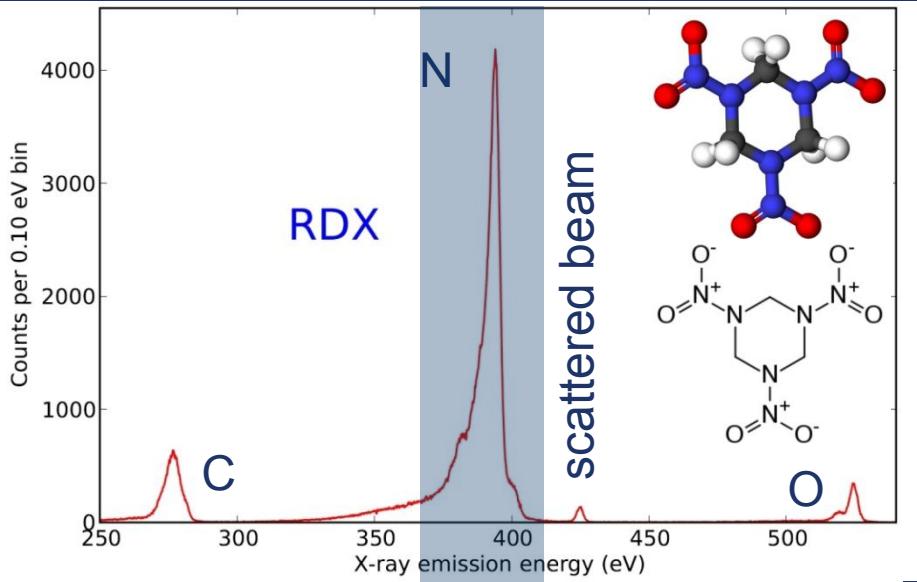
synchrotron spectroscopy

our spectrometer

results

NIST

chemical-shift XES



zoom in on nitrogen peak
in each spectrum:

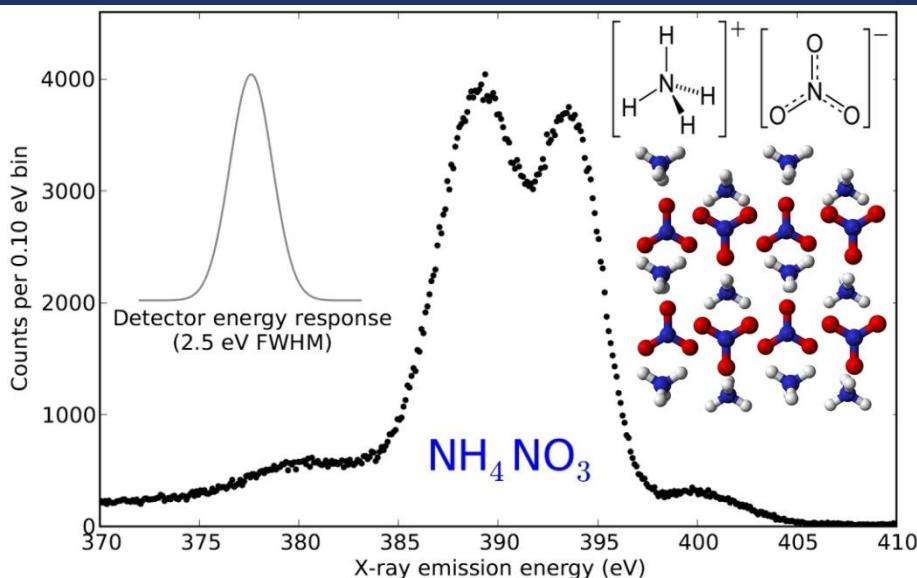
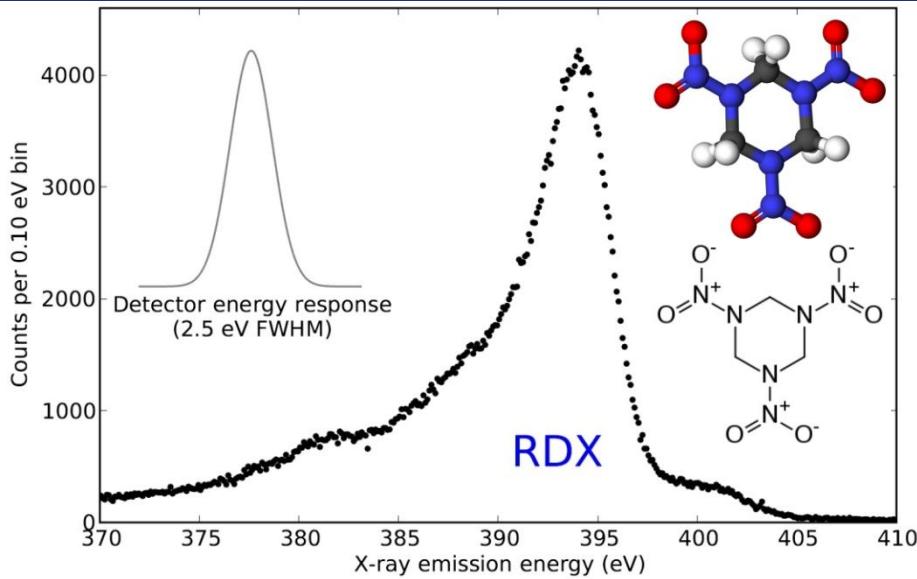


synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

chemical-shift XES



RDX is clearly distinguishable from NH_4NO_3 .



synchrotron spectroscopy

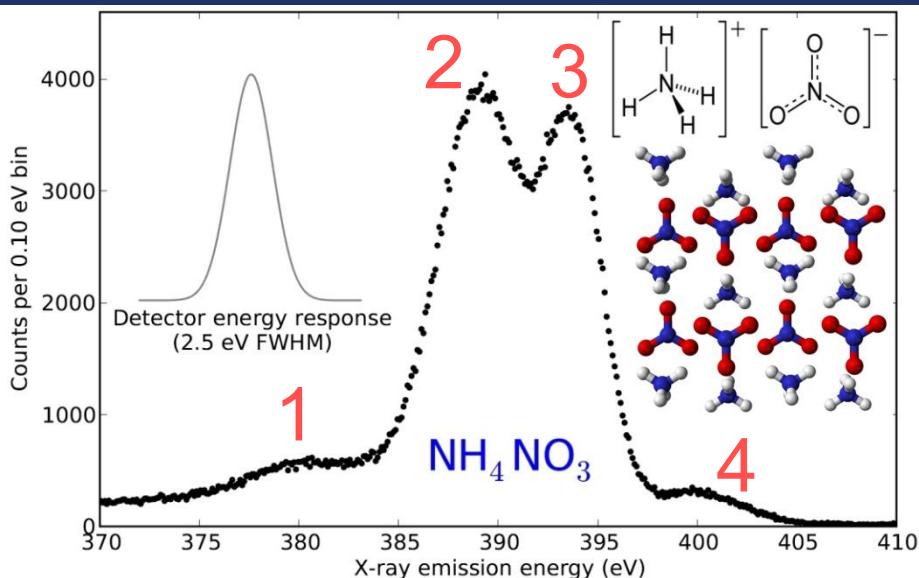
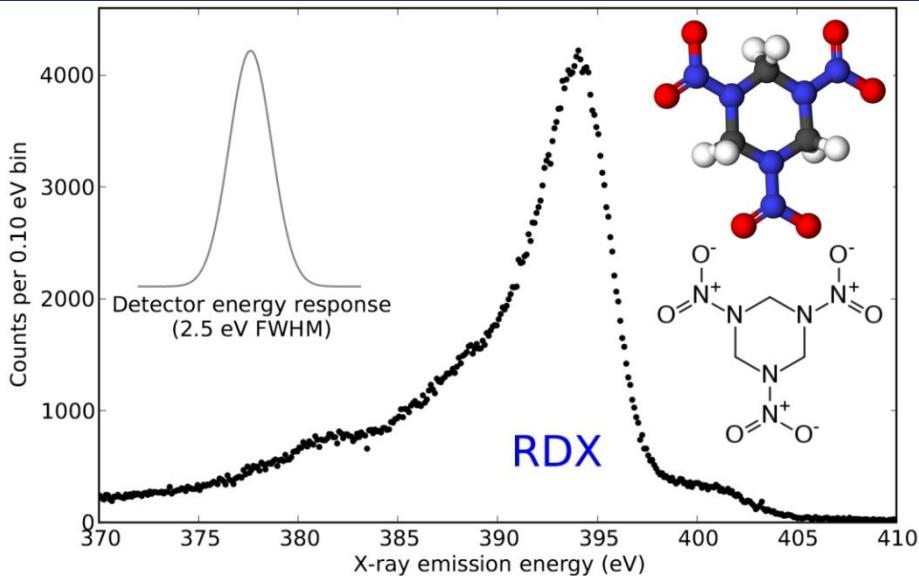
our spectrometer

results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

chemical-shift XES



further, NH₄NO₃ has four resolved features that are associated with:

- NH₄⁺ (highly reduced N)
(2)
- NO₃⁻ (highly oxidized N)
(1, 3, 4)

(feature ID's from F.D. Vila, et al.,
J Phys. Chem. A, 115, 3243-3250 [2011])



synchrotron spectroscopy

our spectrometer

results

NIST

PFY-NEXAFS

second example application:

partial-fluorescence-yield
near-edge X-ray absorption fine structure
(PFY-NEXAFS)

map unoccupied D.O.S.



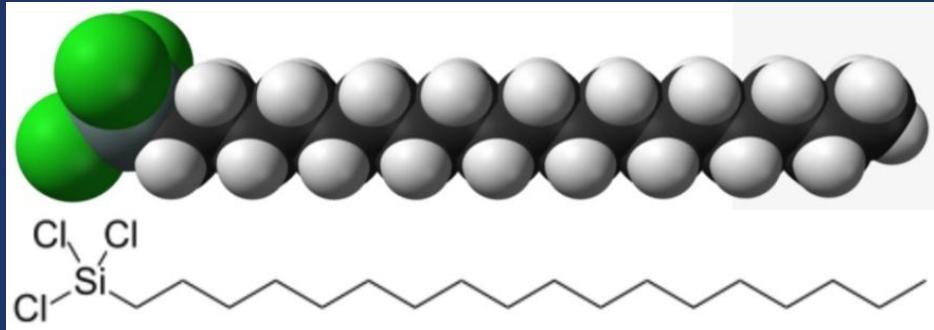
synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

PFY-NEXAFS

a difficult sample: NIST standard reference material (SRM) 1216-I



want to do carbon-edge absorption spectroscopy

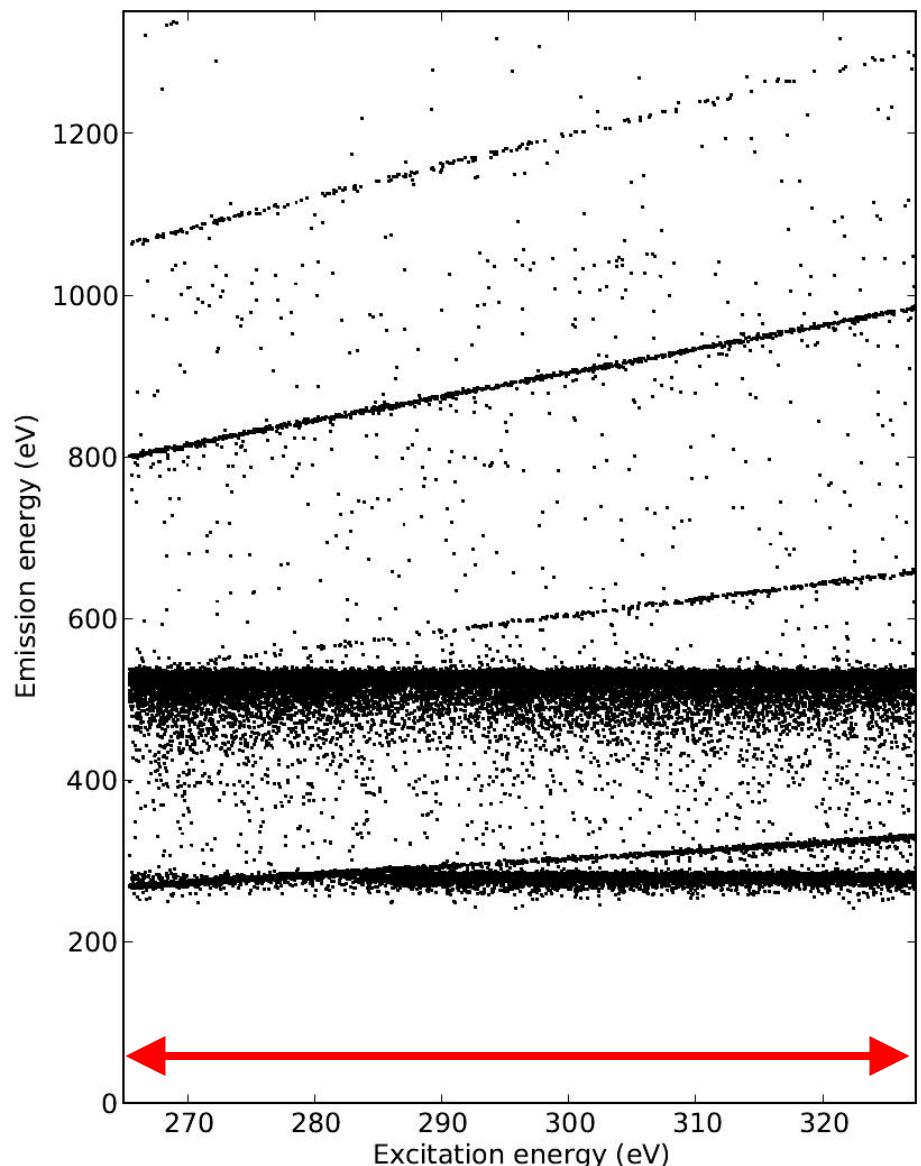


synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

PFY-NEXAFS



emission collected
simultaneously from
200 eV to 1400 eV by
TES array

(beamline produces no
photons above 1400 eV)

beamline monochromator
scanned from 265 to 327 eV
(across C edge)



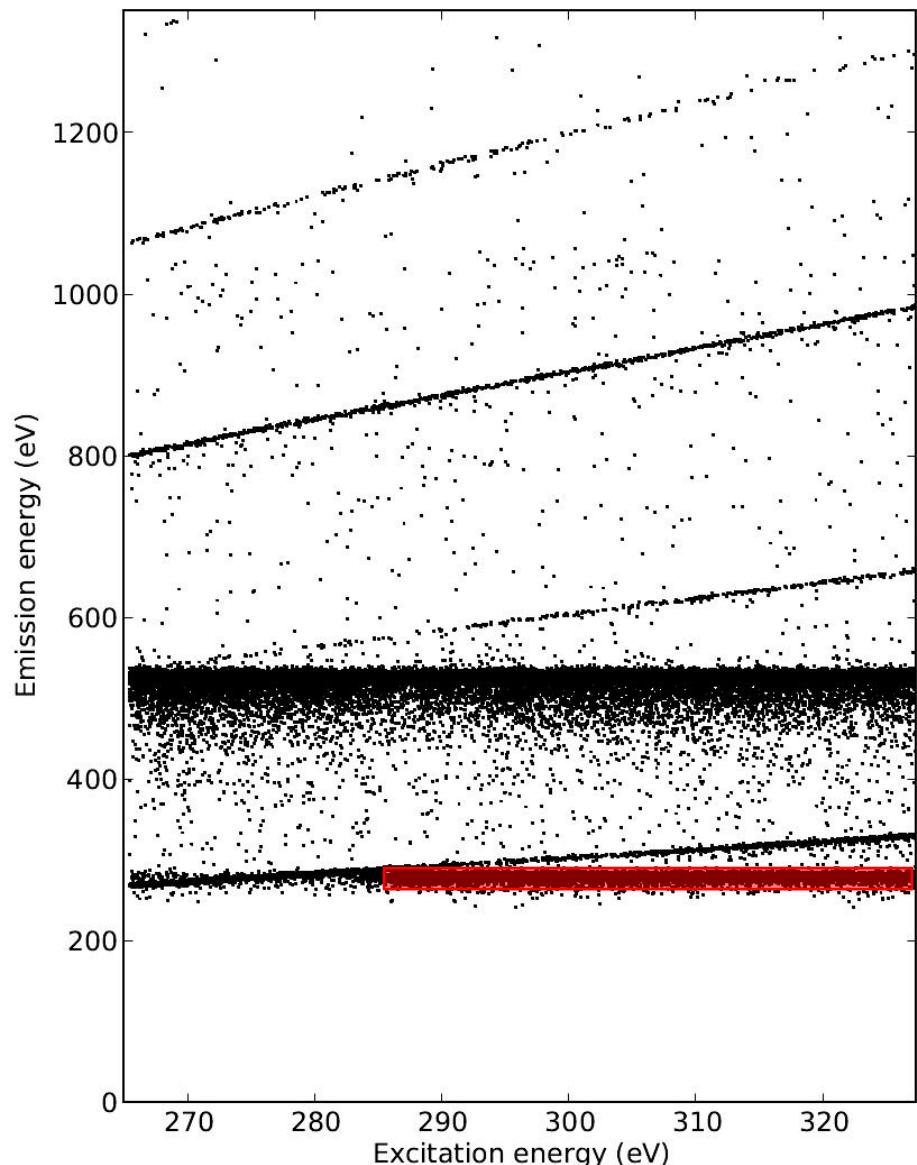
synchrotron spectroscopy

our spectrometer

results

NIST

PFY-NEXAFS



- each point is an X-ray
- 1.6 million X-rays in 20 minute scan
- < 10% of total data plotted for clarity

← C K α : desired signal
(track strength vs. E_{beam})

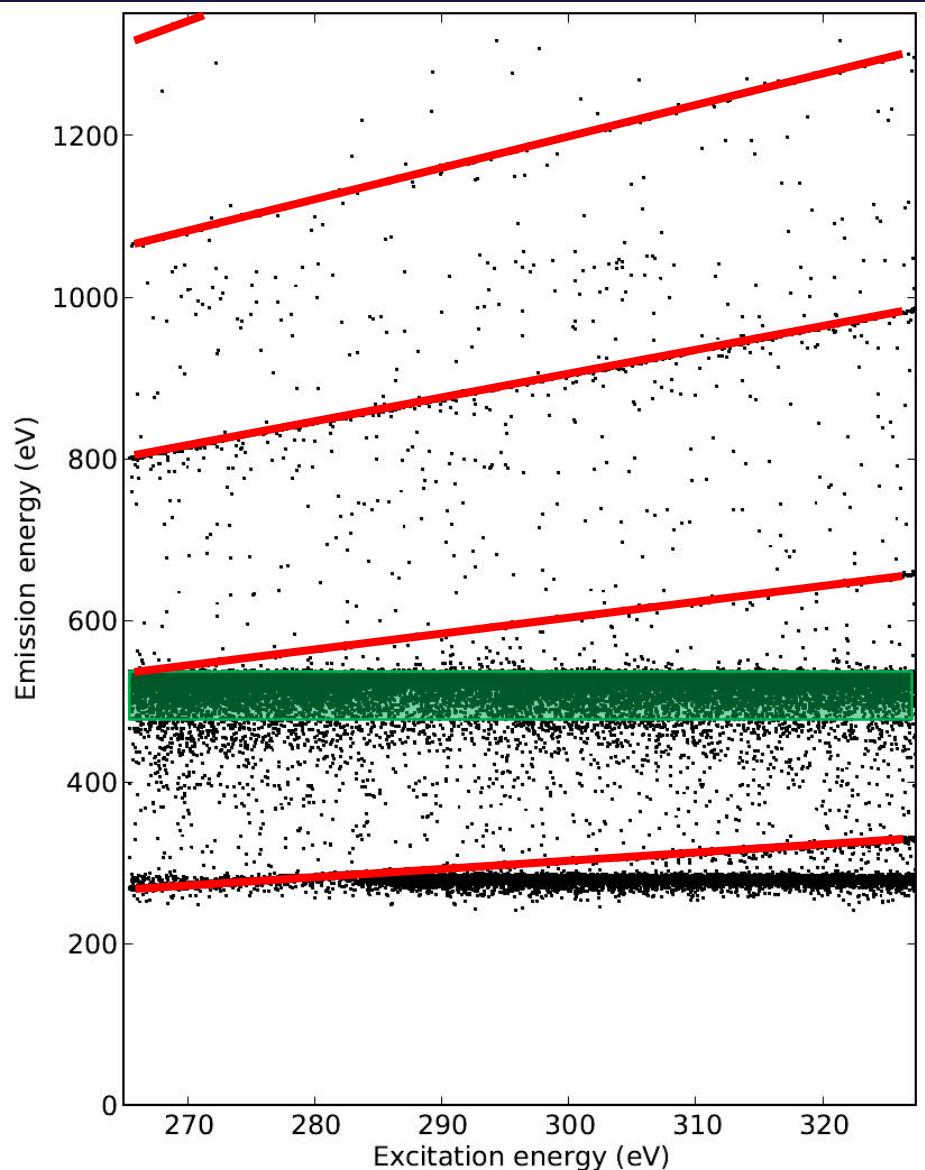
synchrotron spectroscopy

our spectrometer

results

NIST

PFY-NEXAFS



backgrounds:

harmonics 1 – 5 of
scattered beam

O K α (excited by harmonics)



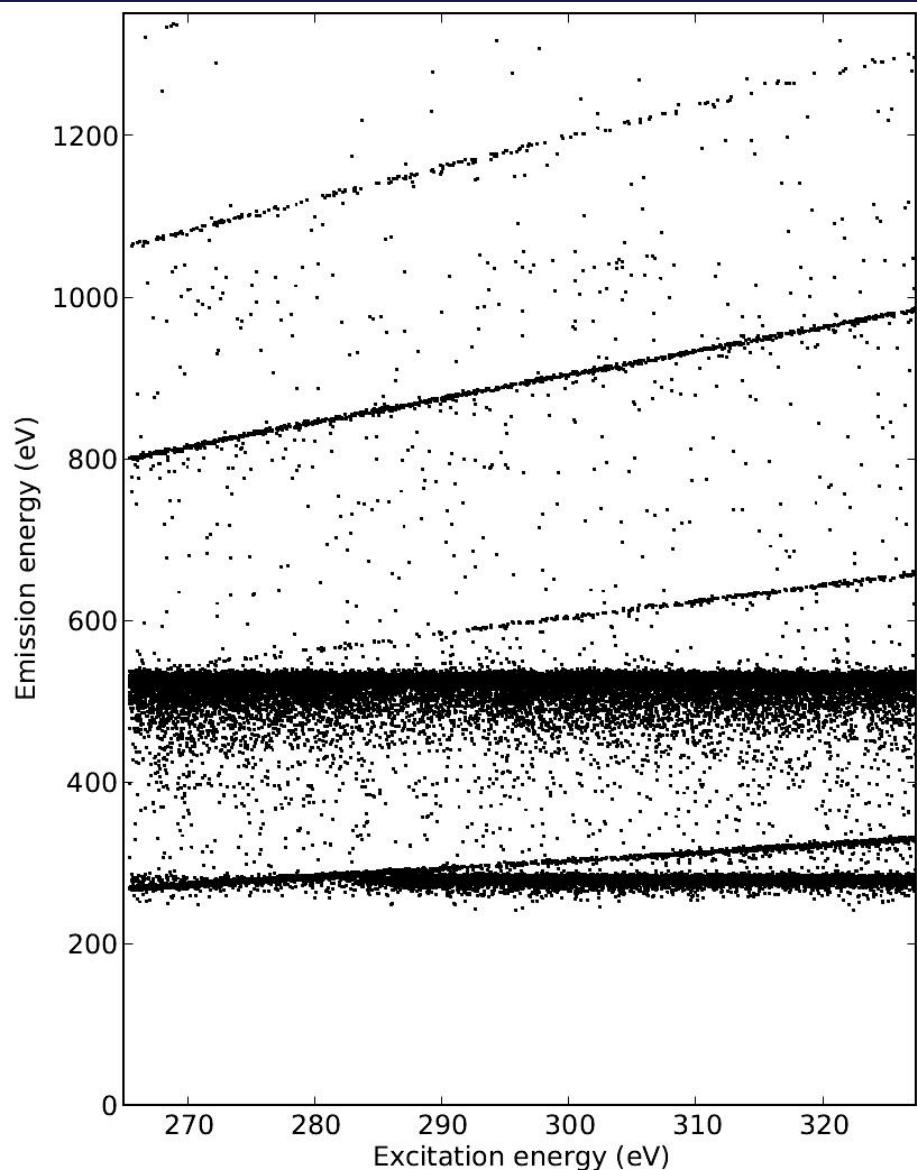
synchrotron spectroscopy

our spectrometer

results

NIST

PFY-NEXAFS



zoom



synchrotron spectroscopy

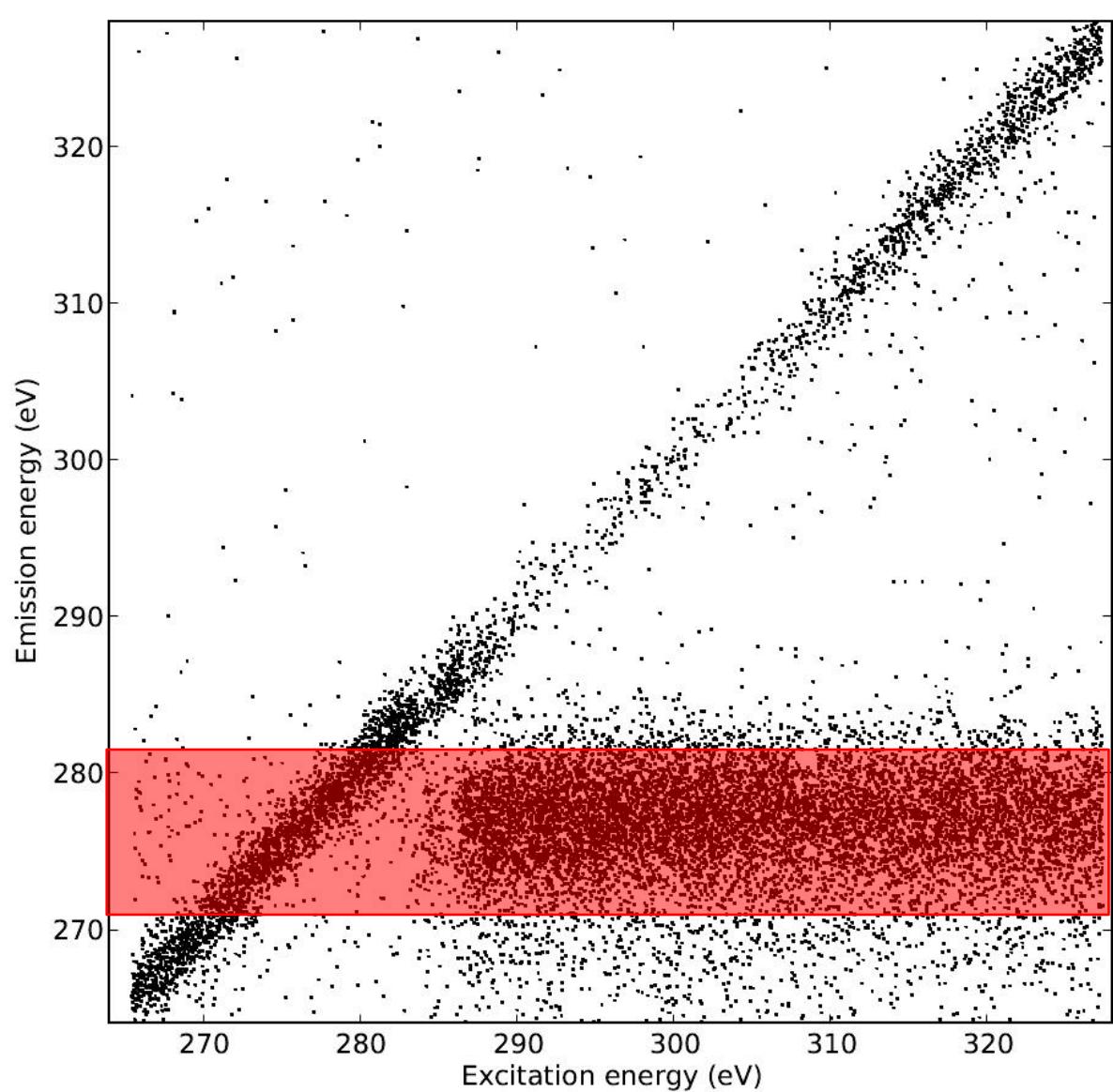
our spectrometer

results

NIST

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

PFY-NEXAFS



window on C K α ,
histogram

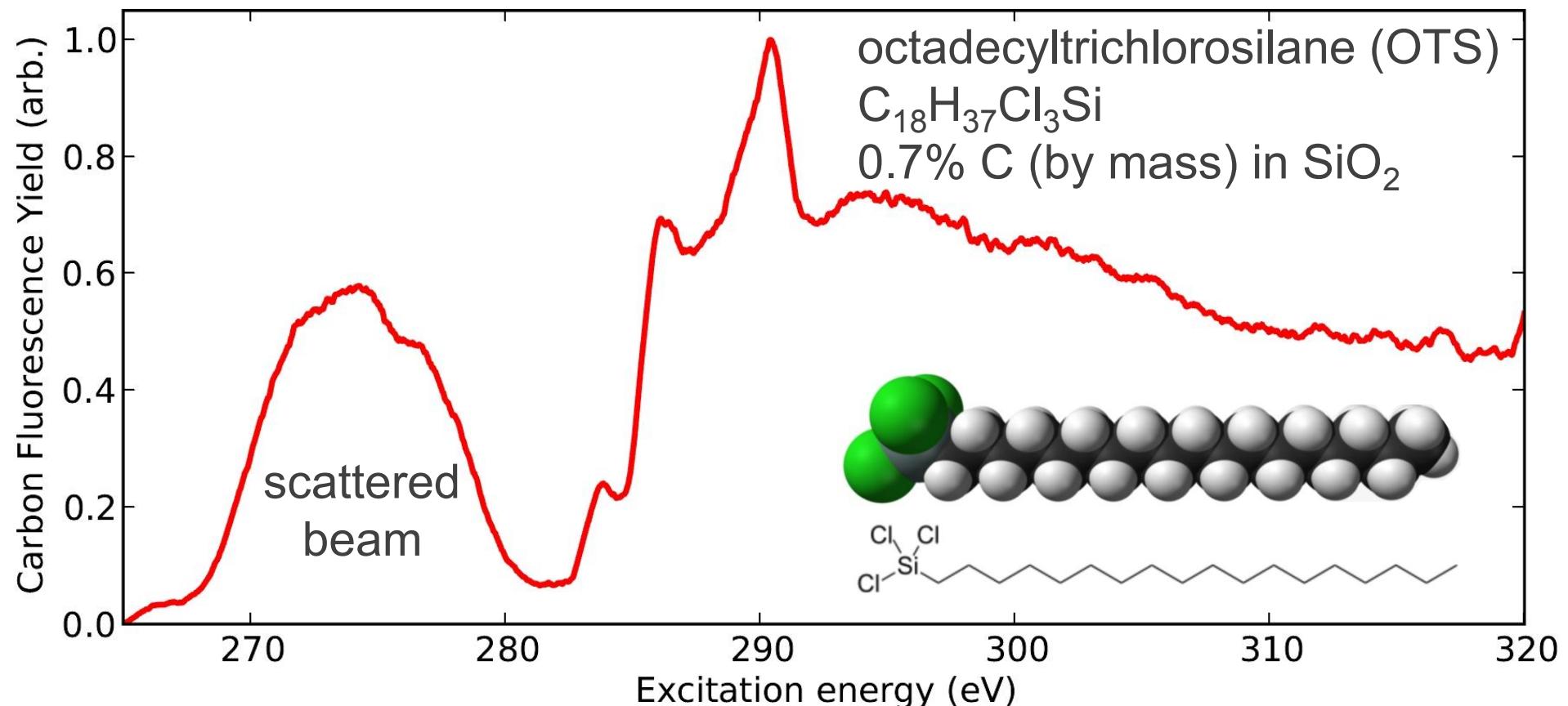


synchrotron spectroscopy our spectrometer results

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST

PFY-NEXAFS



resulting NEXAFS spectrum



synchrotron spectroscopy

our spectrometer

results

NIST

conclusions

- best-ever ΔE achieved at a synchrotron by an energy-dispersive X-ray spectrometer
- observed chemical shifts in XES data at 400 eV:
 - 45 sensors optimized for 5–10 keV X-rays
 - sample receiving $\sim 6 \times 10^9 \gamma/\text{s}$ on a BM beamline
- kilo-sensor spectrometer under development:
 - $\Delta E_{\text{FWHM}} \rightarrow 0.5–1 \text{ eV} \quad (E_\gamma < 700 \text{ eV})$
 - toward 1 MHz / array-rate!



doriese@boulder.nist.gov

W.B. Doriese, TES Workshop @ ASC (Portland), October 8, 2012

NIST